


<b>Search Notes</b> 	<b>Application/Control No.</b> 10577815	<b>Applicant(s)/Patent Under Reexamination</b> SCHERBLE ET AL.
	<b>Examiner</b> Jeffrey Lenihan	<b>Art Unit</b> 1796

SEARCHED			
Class	Subclass	Date	Examiner
521	149, 125, 150, 183, 128, 117, 145	5/14/2009	/JL/

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search in eDAN/PALM	5/14/2009	/JL/
see attached EAST history	5/14/2009	/JL/
online search	5/14/2009	/JL/
updated EAST history	11/30/2009	/JL/
updated EAST history	4/7/2010	/JL/
updated EAST history	8/10/2010	/JL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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